FORM P	FORM PTO-1449											Docket Num (Optional) Application No. 100-14010 (P04871-P01) 10/091,982				
	VINE	OB	AJA	TIO	N D	ISCI	os	URE	CITATION							
	٠, ر	~	5	N A	N A	PPL	.ICA	TIO	N	Applicant(s) Abdalla Aly Naem						
1	JL 23				eral s	shee	ts if	nece	essary)					Group Art Unit 2824		
PER	FTRADE	MAR							U.S. P	ATENT DOC	UMENTS					
EXAMI			MEN	T NI	JMB	ER	•	DATE		ME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE			
COW		3	9	2	8	0	9	3	12/23/75	Van Tongerloo et al.		148	186	06/03/74		
		5	6	0	8	2	3	7	03/04/97	Aizawa et al.		257	132	03/13/95	5	
		3	9	3	7	5	7	9	02/10/76	Schmidt		356	144	11/15/73		
		4	1	8	9	8	2	0	02/26/80	Slack		29	425	25 02/21/78		
	-	4	2	6	1	7	8	1	04/14/81	Edmonds e	t al.	156	254	01/31/79		
		4	7	8	2	0	2	8	11/01/88	Farrier et al.		437	3	08/27/87		
		5	1	4	2	7	5	6	09/01/92	Ibaraki et al.		29	25.01	10/19/90	10/19/90	
		5	2	4	0	8	8	2	08/31/93	Satoh et al.		437	226	26 07/28/92		
		5	5	3	0	5	5	2	06/25/96	Mermagen	et al.	356	401	12/28/9		
		5	3	6	2	6	8	3	11/08/94	Takenaka e	t al.	437	226	03/04/94	1	
		5	7	3	9	0	6	7	04/14/98	DeBusk et	al.	438	618	12/07/95		
CDL	S	5	2	5	0	4	6	0	10/05/93	Yamagata 6	et al.	437	62	10/09/92		
									FOREIGN	PATENT DO	CUMENTS					
			ООС	UME	ENT	NUN	/BEI	R	DATE	1	NTRY	CLASS	SUBCLASS	Transla	γ	
		6	4	1	9	7	2	9	01/23/89	Japan		H01L	021/304	Yes	No X	
COL	7			<u></u>		1		<u></u>					1			
· · · · · · · · · · · · · · · · · · ·				(НТС	ER C	OC	UME	NTS (Includi	ing Author, 1	itle, Date, Pe	ertinent Pages,	Etc.)			
			<u> </u>													
EXAMIN	IFR					_			DATE CO	ONSIDERED	1 .					
	\mathcal{C}	hr	sto	<u>~</u>	W	.15.					7/28/03					
												ce with MPEP § h next commur				

FORM PTO-14		<u>`</u>					-		10	ocket Nu 00-14010	Optional O (P04871-P01	' '	Application No. 10/091,982		
JUL 2		•	P (A)		ISC APPI			E CITATION ON	A	Applicant(s) Abdalla Aly Naem					
JOE Z				eral :	shee	ts if	nec	essary)		ling Date arch 6, 2		Group Ar 2824	Group Art Unit 2824		
117	UCIN							U.S. P	ATENT DOCUM	IENTS					
EXAMINER INITIAL	DC	CU	MEN	TN	UME	BER		DATE	NAME		CLASS	SUBCLASS	FILING DATE IF APPROPRIATE		
W W	6	0	1	0	9	5	1	01/04/00	Pushpala et al.		438	458	04/14/9		
	6	2	2	1	7	6	9	04/24/01	Dhong et al.		438	667	03/05/99		
	6	1	8	7	6	7	7	02/13/01	Ahn		438	667	08/22/97		
	6	1	1	0	8	2	5	08/29/00	Mastromatteo	et al.	438	667	11/25/98		
00 W	5	1	6	6	0	9	7	11/24/92	Tanielian		437	203	203 11/26/9		
		_						FOREIGN	PATENT DOCL	JMENTS					
	1	DOC	UME	ENT	NUN	ЛВЕІ	R	DATE	COUNTRY		CLASS	SUBCLASS	Translation No.		
													Yes	No	
	L	<u> </u>	l	L			<u></u>		<u></u>			1			
			(ЭТН	ER C	OC	UME	NTS (Includi	ing Author, Title	, Date, Po	ertinent Pages,	Etc.)			

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP §609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

PTO/SB/08 (10-92)

EXAMINER

Patent and Trademark Office; U.S. DEPARTMENT OF COMMERCE